



# Poster: Computer Analysis and Simulation of Strain Limiting Models With Linearized Strain

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# Strain limiting model - motivation

**Materials with strain limiting behavior (norm of strain is bounded):**

- Soft tissues
- Polymers
- Brittle materials

## Nomenclature

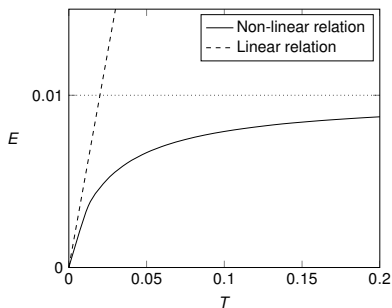
- $\mathbf{T}$  ... Cauchy stress
- $\mathbf{u}$  ... Displacement vector
- $\mathbf{E}$  ... Green-St. Venant tensor  $\mathbf{E} = \frac{1}{2}(\nabla \mathbf{u} + (\nabla \mathbf{u})^T + (\nabla \mathbf{u})^T \nabla \mathbf{u})$
- $\boldsymbol{\varepsilon}$  ... Linearized strain  $\boldsymbol{\varepsilon} = \frac{1}{2}(\nabla \mathbf{u} + (\nabla \mathbf{u})^T)$

## Implicit constitutive theory

- $\hat{\mathbf{G}}(\mathbf{E}, \mathbf{T}) = \mathbf{0}$ , special explicit case  $\mathbf{E} = \mathbf{G}(\mathbf{T})$

Proposed in [Rajagopal, 2010]

$$\mathbf{E} = \gamma \left( 1 - \exp \frac{-\lambda \operatorname{tr} \mathbf{T}}{1 + \|\mathbf{T}\|} \right) \mathbf{I} + \frac{\mathbf{T}}{2\mu (1 + \kappa \|\mathbf{T}\|^a)^{\frac{1}{a}}}. \quad (1)$$



**Figure:** One dimensional stress strain relation for  $\mu = 1$ ,  $a = 0.9$  and  $\kappa = 24.8$ .

## Small displacement gradient assumption

- Assuming  $\|\nabla \mathbf{u}\|_\infty \ll 1$
- Under this assumption we can approximate Green-St. Venant strain tensor  $\mathbf{E}$  by linearized strain  $\boldsymbol{\varepsilon}$
- Neglecting term  $((\nabla \mathbf{u})^T \nabla \mathbf{u})/2$
- $\|\nabla \mathbf{u}\|_\infty \ll 1$  is not always true for Hookean model applications (Linear Elastic Fracture Mechanics). Stress limiting model may fulfill the condition  $\|\nabla \mathbf{u}\|_\infty \ll 1$  by proper setting of model parameters.
- Linearizing  $\mathbf{E}$  does not mean to linearize constitutive relation.
- Strain limiting model is actively studied from the point of view of modeling, analysis and numerics.

## System of equations for tensor $\mathbf{T}$ , tensor $\boldsymbol{\varepsilon}$ and vector $\mathbf{u}$

$$\operatorname{div} \mathbf{T} = \mathbf{f}, \quad \mathbf{T} = \mathbf{T}^T, \quad (2a)$$

$$\boldsymbol{\varepsilon} = \mathbf{G}(\mathbf{T}), \quad (2b)$$

$$\boldsymbol{\varepsilon} = \frac{1}{2} (\nabla \mathbf{u} + (\nabla \mathbf{u})^T). \quad (2c)$$

## System of equations for tensor $\mathbf{T}$ and tensor $\boldsymbol{\varepsilon}$

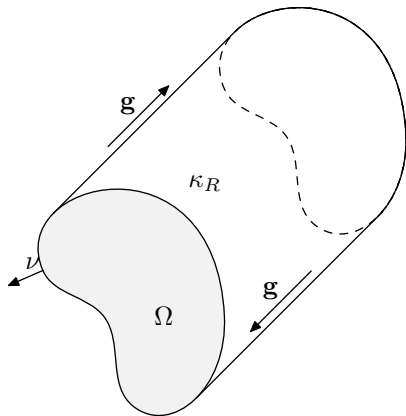
$$\operatorname{div} \mathbf{T} = \mathbf{f}, \quad (3a)$$

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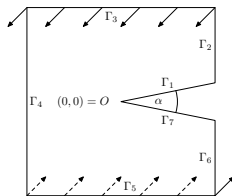
$$\boldsymbol{\varepsilon}_{ij,kl} + \boldsymbol{\varepsilon}_{kl,ij} - \boldsymbol{\varepsilon}_{ik,jl} - \boldsymbol{\varepsilon}_{jl,ik} = 0, \quad i, j, k, l \in 1, 2, 3. \quad (3c)$$

# Antiplane stress

In antiplane stress problem the only nonzero components of the stress tensor  $\mathbf{T}$  are  $T_{13}$  and  $T_{23}$ .  $T_{11} = T_{22} = T_{33} = T_{12} = 0$ . We also assume that  $T_{23}$  and  $T_{13}$  depend only on  $x_1$  and  $x_2$ .



V shaped cutout, variable  $\alpha$  loaded (top and bottom) by shear force  $F$ .

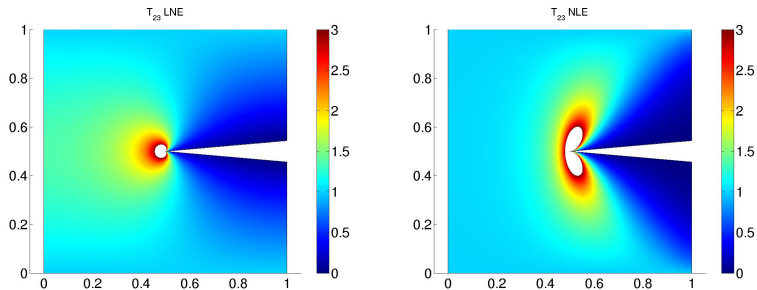


**Figure:** Computational domain.

Aim is to compare linear elasticity model with nonlinear strain limiting model both with linearized strain tensor  $\varepsilon$ . For details see [Kulvait et al., 2013].

# Stress distribution comparison

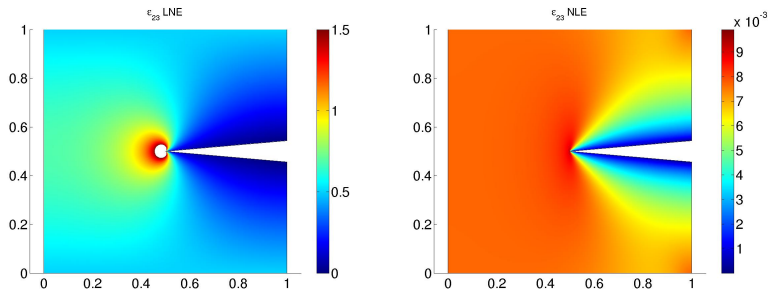
**Figure:** Comparison of  $T_{23}$  for linear (left) and nonlinear (right) model.





# Strain distribution comparison

**Figure:** Comparison of  $\varepsilon_{23}$  linear (left) and nonlinear (right) model.





Kulvait, V., Málek, J., and Rajagopal, K. (2013).

Anti-plane stress state of a plate with a v-notch for a new class of elastic solids.

*International Journal of Fracture*, 179(1-2):59–73.



Rajagopal, K. (2010).

On a new class of models in elasticity.

*Mathematical and Computational Applications*, 15(4):506–528.